

**Notice of References Cited**

Application/Control No.

10/552,312

Applicant(s)/Patent Under  
Reexamination  
HAMADA, TAKESHI

Examiner

David E. Bochna

Art Unit

3679

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,082,324 A	04-1978	Obrecht, Robert E.	285/124.5
*	B	US-5,704,399 A	01-1998	Hayashi et al.	137/884
*	C	US-5,881,773 A	03-1999	Lukas et al.	137/884
*	D	US-6,237,634 B1	05-2001	Narita et al.	137/625.27
*	E	US-6,733,044 B2	05-2004	Huang, Yin Hsiang	285/124.1
*	F	US-6,832,788 B2	12-2004	Fukano et al.	285/124.5
*	G	US-7,073,825 B2	07-2006	Takada et al.	285/124.1
*	H	US-7,178,556 B2	02-2007	Reid et al.	137/884
*	I	US-7,300,075 B2	11-2007	Ebskamp et al.	285/208
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.